ICS8543I

Differential-to-4, Differential-to-LVDS Fanout Buffer

DATA SHEET

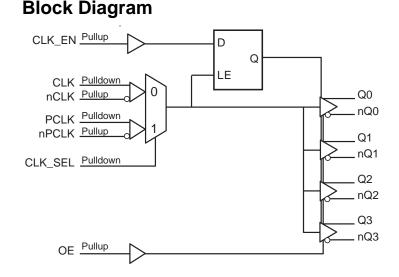
General Description

The ICS8543I is a low skew, high performance 1-to-4 Differential-to-LVDS Clock Fanout Buffer. Utilizing Low Voltage Differential Signaling (LVDS) the ICS8543I provides a low power, low noise, solution for distributing clock signals over controlled impedances of 100Ω . The ICS8543I has two selectable clock inputs. The CLK, nCLK pair can accept most standard differential input levels. The PCLK, nPCLK pair can accept LVPECL, CML, or SSTL input levels. The clock enable is internally synchronized to eliminate runt pulses on the outputs during asynchronous assertion/deassertion of the clock enable pin.

Guaranteed output and part-to-part skew characteristics make the ICS8543I ideal for those applications demanding well defined performance and repeatability.

Features

- Four differential LVDS output pairs
- Selectable differential CLK/nCLK or LVPECL clock inputs
- CLK/nCLK pair can accept the following differential input levels: LVPECL, LVDS, LVHSTL, SSTL, HCSL
- PCLK/nPCLK pair can accept the following differential input levels: LVPECL, CML, SSTL
- Maximum output frequency: 650MHz
- Translates any single-ended input signals to LVDS levels with resistor bias on nCLK input
- Additive phase Jitter, RMS: 0.164ps (typical)
- Output skew: 40ps (maximum)
- Part-to-part skew: 600ps (maximum)
- Propagation delay: 2.6ns (maximum)
- Full 3.3Vsupply mode
- -40°C to 85°C ambient operating temperature
- Available in lead-free packages



Pin Assignment

GND□	1	20	_ Q0
CLK_EN	2	19	🗆 nQ0
CLK_SEL	3	18	
CLK	4	17	□Q1
nCLK	5	16	🗌 nQ1
PCLK	6	15	🗆 Q2
nPCLK	7	14	🗌 nQ2
OE	8	13	GND
GND 🗌	9	12	⊒Q3
V _{DD}	10	11	🗆 nQ3

ICS8543I

20-Lead TSSOP 6.5mm x 4.4mm x 0.925mm package body G Package Top View

Table 1. Pin Descriptions

Number	Name	Ту	pe	Description
1, 9, 13	GND	Power		Power supply ground.
2	CLK_EN	Input	Pullup	Synchronizing clock enable. When HIGH, clock outputs follows clock input. When LOW, Qx outputs are forced low, nQx outputs are forced high. LVCMOS / LVTTL interface levels.
3	CLK_SEL	Input	Pulldown	Clock select input. When HIGH, selects PCLK/nPCLK inputs. When LOW, selects CLK/nCLK inputs. LVCMOS / LVTTL interface levels.
4	CLK	Input	Pulldown	Non-inverting differential clock input.
5	nCLK	Input	Pullup	Inverting differential clock input.
6	PCLK	Input	Pulldown	Non-inverting differential LVPECL clock input.
7	nPCLK	Input	Pullup	Inverting differential LVPECL clock input.
8	OE	Input	Pullup	Output enable. Controls enabling and disabling of outputs Q0/nQ0 through Q3/nQ3. LVCMOS/LVTTL interface levels.
10, 18	V _{DD}	Power		Positive supply pins.
11, 12	nQ3, Q3	Output		Differential output pair. LVDS interface levels.
14, 15	nQ2, Q2	Output		Differential output pair. LVDS interface levels.
16, 17	nQ1, Q1	Output		Differential output pair. LVDS interface levels.
19, 20	nQ0, Q0	Output		Differential output pair. LVDS interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ

Function Tables

Table 3A. Control Input Function Table

	Inp	Outputs			
OE	CLK_EN	CLK_SEL	Selected Source	Q0:Q3	nQ0:nQ3
0	Х	Х		Hi-Z	Hi-Z
1	0	0	CLK/nCLK	Disabled; Low	Disabled; High
1	0	1	PCLK/nPCLK	Disabled; Low	Disabled; High
1	1	0	CLK/nCLK	Enabled	Enabled
1	1	1	PCLK/nPCLK	Enabled	Enabled

After CLK_EN switches, the clock outputs are disabled or enabled following a rising and falling input clock edge as shown in Figure 1. In the active mode, the state of the outputs are a function of the CLK/nCLK and PCLK/nPCLK inputs as described in Table 3B.

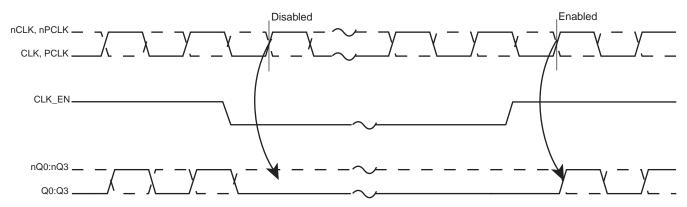


Figure 1. CLK_EN Timing Diagram

Table 3B. Clock Input Function Table	
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Inp	outs	Outputs			
CLK or PCLK	nCLK or nPCLK	Q[0:3]	nQ[0:3]	Input to Output Mode	Polarity
0	1	LOW	HIGH	Differential to Differential	Non-Inverting
1	0	HIGH	LOW	Differential to Differential	Non-Inverting
0	Biased; NOTE 1	LOW	HIGH	Single-Ended to Differential	Non-Inverting
1	Biased; NOTE 1	HIGH	LOW	Single-Ended to Differential	Non-Inverting
Biased; NOTE 1	0	HIGH	LOW	Single-Ended to Differential	Inverting
Biased; NOTE 1	1	LOW	HIGH	Single-Ended to Differential	Inverting

NOTE 1: Please refer to the Application Information section, Wiring the Differential Input to Accept Single-Ended Levels.

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V _{DD}	4.6V
Inputs, V _I	-0.5V to V _{DD} + 0.5V
Outputs, I _O	
Continuos Current	10mA
Surge Current	15mA
Package Thermal Impedance, θ_{JA}	73.2°C/W (0 lfpm)
Storage Temperature, T _{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 4A. Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{DD}	Positive Supply Voltage		3.135	3.3	3.465	V
I _{DD}	Power Supply Current				50	mA

Table 4B. LVCMOS/LVTTL DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V _{IH}	Input High Voltage			2		V _{DD} + 0.3	V
V _{IL}	Input Low Voltage			-0.3		0.8	V
l la mont l là m	Input High Current	OE, CLK_EN	$V_{DD} = V_{IN} = 3.465V$			5	μA
Ιн	input riigh Current	CLK_SEL	$V_{DD} = V_{IN} = 3.465 V$				μA
	Input Low Current	OE, CLK_EN	V _{DD} = 3.465V, V _{IN} = 0V	-150			μA
L	Input Low Current	CLK_SEL	$V_{DD} = 3.465 V, V_{IN} = 0 V$	-5			μA

Table 4C. Differential DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
I _{IH} Input High Current	Input High Current	CLK	V _{DD} = V _{IN} = 3.465V			150	μA
	nCLK	$V_{DD} = V_{IN} = 3.465V$			5	μA	
I _{IL} Input Low Current	CLK	V _{DD} = 3.465V, V _{IN} = 0V	-5			μA	
	Input Low Current	nCLK	V _{DD} = 3.465V, V _{IN} = 0V	-150			μA
V _{PP}	Peak-to-Peak Volta	ige; NOTE 1		0.15		1.3	V
V _{CMR}	Common Mode Inp NOTE 1, 2	ut Voltage;		0.5		V _{DD} – 0.85	V

NOTE 1: V_{IL} should not be less than -0.3V.

NOTE 2: Common mode input voltage is defined as VIH.

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
I	Input High Current	PCLK	V _{DD} = V _{IN} = 3.465V			150	μA
Ιн	Input High Current	nPCLK	V _{DD} = V _{IN} = 3.465V			5	μA
1	Input Low Current	PCLK	V _{DD} = 3.465V, V _{IN} = 0V	-5			μA
IL	Input Low Current	nPCLK	V _{DD} = 3.465V, V _{IN} = 0V	-150			μA
V _{PP}	Peak-to-Peak Voltage; NOTE 1			0.3		1	V
V _{CMR}	Common Mode Input Vol NOTE 1, 2	tage;		1.5		V _{DD}	V

Table 4D. LVPECL DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

NOTE 1: V_{IL} should not be less than -0.3V.

NOTE 2: Common mode input voltage is defined as VIH.

Table 4E. LVDS DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{OD}	Differential Output Voltage		200	280	360	mV
ΔV_{OD}	V _{OD} Magnitude Change			0	40	mV
V _{OS}	Offset Voltage		1.125	1.25	1.375	V
ΔV_{OS}	V _{OS} Magnitude Change			5	25	mV
l _{Oz}	High Impedance Leakage		-10		+10	μA
I _{OFF}	Power Off Leakage		-20	±1	+20	μA
I _{OSD}	Differential Output Short Circuit Current			-3.5	-5	mA
I _{OS}	Output Short Circuit Current			-3.5	-5	mA
V _{OH}	Output Voltage High			1.34	1.6	V
V _{OL}	Output Voltage Low		0.9	1.06		V

AC Electrical Characteristics

Table 5. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Parameter	ter Symbol		neter Symbol		Test Conditions Minimum		Typical	Maximum	Units	
f _{MAX}	Maximum Output Frequen	ю				650	MHz			
<i>t</i> jit	Buffer Additive Phase Jitte refer to Additive Phase Jitt		153.6MHz, Integration Range: 12kHz – 20MHz		0.164		ps			
t _{PD}	Propagation Delay; NOTE 1		$f \le 650 \text{MHz}$	1.5		2.6	ns			
<i>t</i> sk(o)	Output Skew; NOTE 2, 4					40	ps			
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 3, 4					600	ps			
t _R / t _F	Output Rise/Fall Time		20% to 80% @ 50MHz	150		450	ps			
odc	Output Duty Cycle	odc		45	50	55	%			

All parameters measured at 500MHz unless noted otherwise.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at the differential output crosspoints.

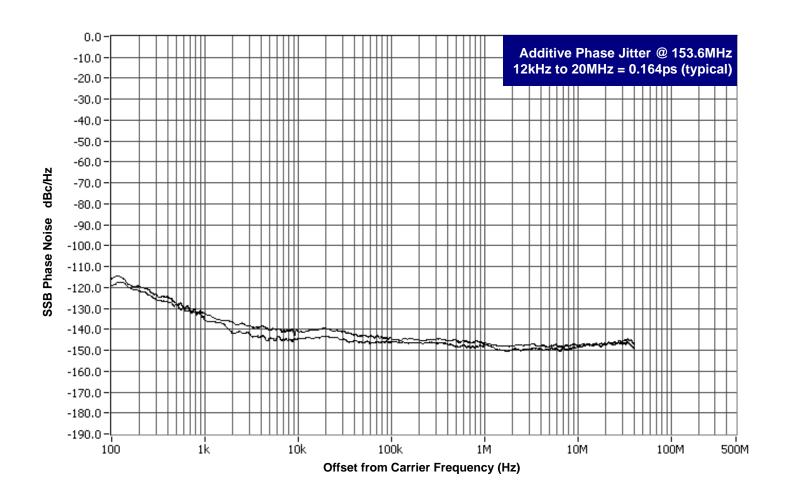
NOTE 3: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential crosspoints.

NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

Additive Phase Jitter

The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise*. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio

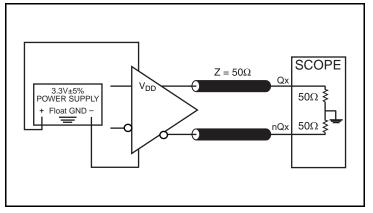
of the power in the 1Hz band to the power in the fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.



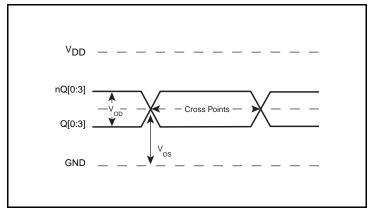
As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

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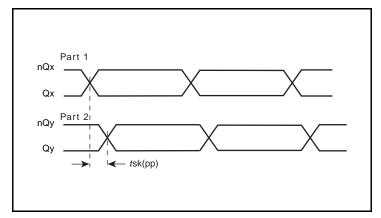
Parameter Measurement Information



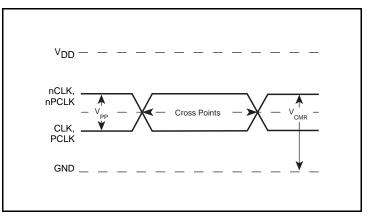
3.3V LVDS Output Load AC Test Circuit



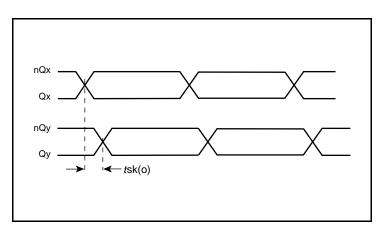
Differential Output Level



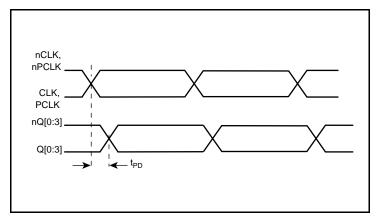
Part-to-Part Skew



Differential Input Level

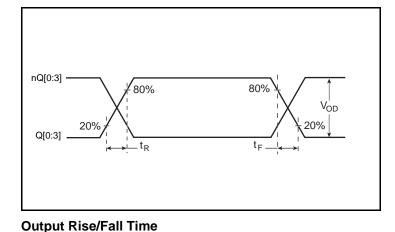


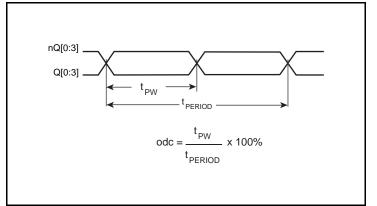




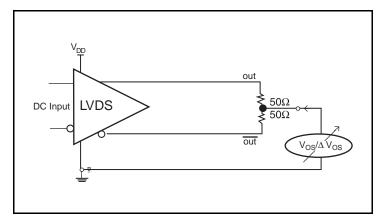


Parameter Measurement Information, continued

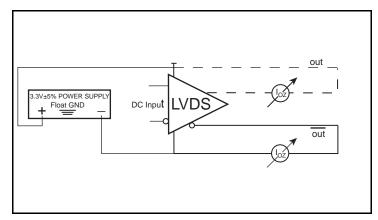




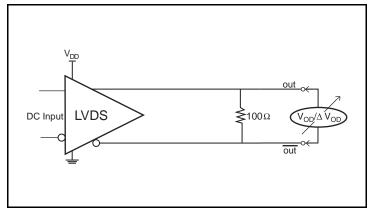
Output Duty Cycle/Pulse Width/Period



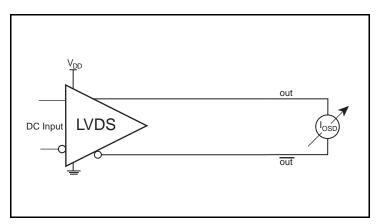
Offset Voltage Setup



High Impedance Leakage Current Setup

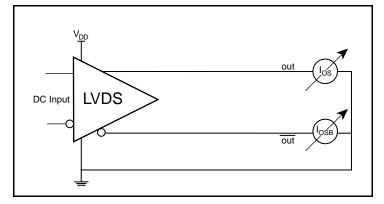


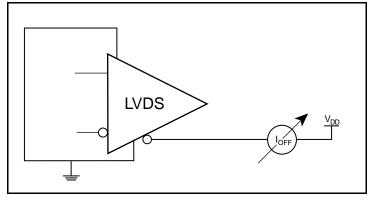




Differential Output Short Circuit Setup

Parameter Measurement Information, continued







Power Off Leakage Setup

Applications Information

Wiring the Differential Input to Accept Single-Ended Levels

Figure 2 shows how a differential input can be wired to accept single ended levels. The reference voltage $V_{REF} = V_{CC}/2$ is generated by the bias resistors R1 and R2. The bypass capacitor (C1) is used to help filter noise on the DC bias. This bias circuit should be located as close to the input pin as possible. The ratio of R1 and R2 might need to be adjusted to position the V_{REF} in the center of the input voltage swing. For example, if the input clock swing is 2.5V and $V_{DD} = 3.3V$, R1 and R2 value should be adjusted to set V_{REF} at 1.25V. The values below are for when both the single ended swing and V_{DD} are at the same voltage. This configuration requires that the sum of the output impedance of the driver (Ro) and the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the input will attenuate the signal in half. This can be done in one of two ways. First, R3 and R4 in parallel should equal the transmission line impedance. For most 50 Ω applications, R3 and R4 can be 100 Ω . The values of the resistors can be increased to reduce the loading for slower and weaker LVCMOS driver. When using single-ended signaling, the noise rejection benefits of differential signaling are reduced. Even though the differential input can handle full rail LVCMOS signaling, it is recommended that the amplitude be reduced. The datasheet specifies a lower differential amplitude, however this only applies to differential signals. For single-ended applications, the swing can be larger, however V_{IL} cannot be less than -0.3V and V_{IH} cannot be more than V_{DD} + 0.3V. Though some of the recommended components might not be used, the pads should be placed in the layout. They can be utilized for debugging purposes. The datasheet specifications are characterized and guaranteed by using a differential signal.

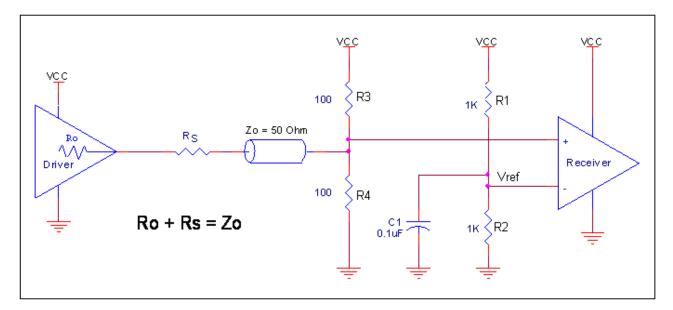


Figure 2. Recommended Schematic for Wiring a Differential Input to Accept Single-ended Levels

Differential Clock Input Interface

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. Both signals must meet the V_{PP} and V_{CMR} input requirements. *Figures 3A to 3F* show interface examples for the CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the

vendor of the driver component to confirm the driver termination requirements. For example, in Figure 3A, the input termination applies for IDT open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.

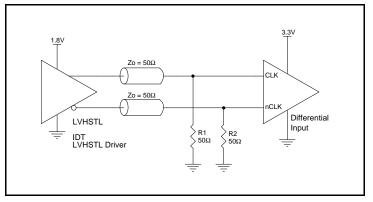


Figure 3A. CLK/nCLK Input Driven by an IDT Open Emitter LVHSTL Driver

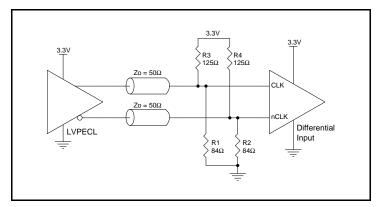
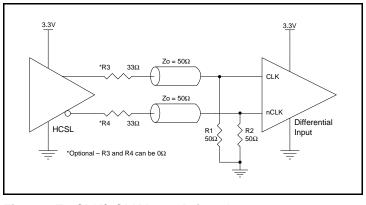


Figure 3C. CLK/nCLK Input Driven by a 3.3V LVPECL Driver





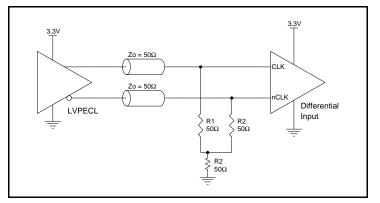


Figure 3B. CLK/nCLK Input Driven by a 3.3V LVPECL Driver

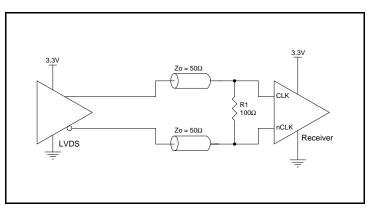
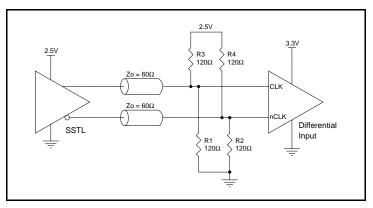
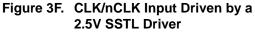


Figure 3D. CLK/nCLK Input Driven by a 3.3V LVDS Driver





LVPECL Clock Input Interface

The PCLK /nPCLK accepts LVPECL, CML, SSTL and other differential signals. Both signals must meet the V_{PP} and V_{CMR} input requirements. *Figures 4A to 4F* show interface examples for the S PCLK/nPCLK input driven by the most common driver types. The

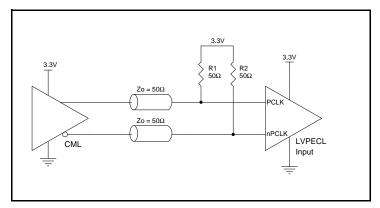
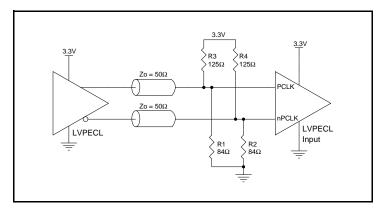
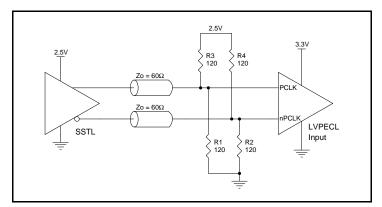


Figure 4A. PCLK/nPCLK Input Driven by a CML Driver









input interfaces suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.

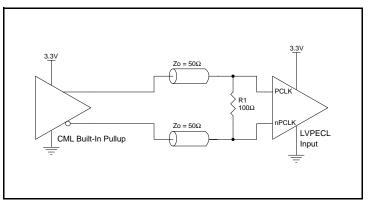


Figure 4B. PCLK/nPCLK Input Driven by a Built-In Pullup CML Driver

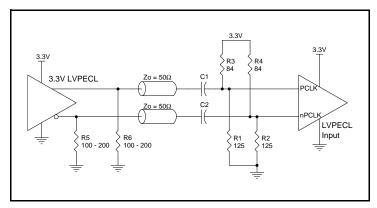
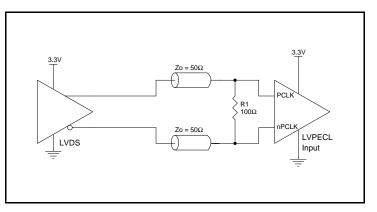


Figure 4D. PCLK/nPCLK Input Driven by a 3.3V LVPECL Driver with AC Couple





Recommendations for Unused Input and Output Pins

Inputs:

CLK/nCLK Inputs

For applications not requiring the use of the differential input, both CLK and nCLK can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from CLK to ground.

PCLK/nPCLK Inputs

For applications not requiring the use of the differential input, both PCLK and nPCLK can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from PCLK to ground.

LVCMOS Control Pins

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A $1k\Omega$ resistor can be used.

LVDS Driver Termination

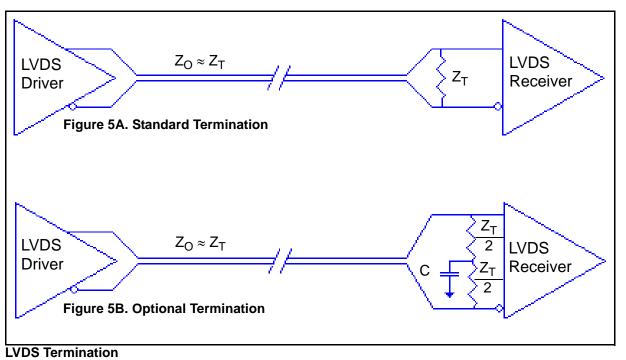
For a general LVDS interface, the recommended value for the termination impedance (Z_T) is between 90 Ω and 132 Ω . The actual value should be selected to match the differential impedance (Z_0) of your transmission line. A typical point-to-point LVDS design uses a 100 Ω parallel resistor at the receiver and a 100 Ω differential transmission-line environment. In order to avoid any transmission-line reflection issues, the components should be surface mounted and must be placed as close to the receiver as possible. IDT offers a full line of LVDS compliant devices with two types of output structures: current source and voltage source. The

Outputs:

LVDS Outputs

All unused LVDS output pairs can be either left floating or terminated with 100Ω across. If they are left floating, there should be no trace attached.

standard termination schematic as shown in *Figure 5A* can be used with either type of output structure. *Figure 5B*, which can also be used with both output types, is an optional termination with center tap capacitance to help filter common mode noise. The capacitor value should be approximately 50pF. If using a non-standard termination, it is recommended to contact IDT and confirm if the output structure is current source or voltage source type. In addition, since these outputs are LVDS compatible, the input receiver's amplitude and common-mode input range should be verified for compatibility with the output.



Power Considerations

This section provides information on power dissipation and junction temperature for the ICS8543I. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the ICS8543I is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

NOTE: Please refer to Section 3 for details on calculating power dissipated in the load.

Power (core)_{MAX} = V_{DD MAX} * I_{DD MAX} = 3.465V * 50mA = **173.25mW**

2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature is 125°C.

The equation for Tj is as follows: Tj = θ_{JA} * Pd_total + T_A

Tj = Junction Temperature

 θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_total = Total Device Power Dissipation (example calculation is in section 1 above)

T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is 73.2°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 85°C with all outputs switching is:

85°C + 0.173W * 73.2°C/W = 97.7°C. This is well below the limit of 125°C.

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

Table 6. Thermal Resitance θ_{JA} for 20 Lead TSSOP, Forced Convection

θ_{JA} by Velocity				
Linear Feet per Minute	0	200	500	
Single-Layer PCB, JEDEC Standard Test Boards	114.5°C/W	98.0°C/W	88.0°C/W	
Multi-Layer PCB, JEDEC Standard Test Boards	73.2°C/W	66.6°C/W	63.5°C/W	

Reliability Information

Table 7. θ_{JA} vs. Air Flow Table for a 20 Lead TSSOP

θ _{JA} by Velocity				
Linear Feet per Minute	0	200	500	
Single-Layer PCB, JEDEC Standard Test Boards	114.5°C/W	98.0°C/W	88.0°C/W	
Multi-Layer PCB, JEDEC Standard Test Boards	73.2°C/W	66.6°C/W	63.5°C/W	

Transistor Count

The transistor count for ICS8543I is: 636

Package Outline and Package Dimensions



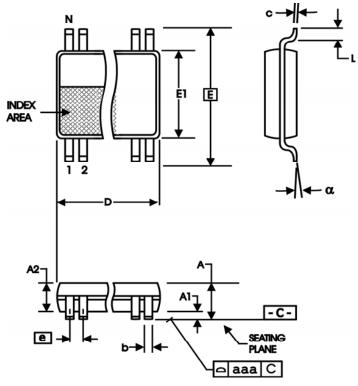


Table 8. Package Dimensions

All	All Dimensions in Millimeters				
Symbol	Minimum	Maximum			
Ν		20			
Α		1.20			
A1	0.05	0.15			
A2	0.80	1.05			
b	0.19	0.30			
C	0.09	0.20			
D	6.40	6.60			
E	6.40) Basic			
E1	4.30	4.50			
е	0.65	5 Basic			
L	0.45	0.75			
α	0°	8°			
aaa		0.10			

Reference Document: JEDEC Publication 95, MO-153

Ordering Information

Table 9. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
8543BGILF	ICS8543BGILF	"Lead-Free" 20 Lead TSSOP	Tube	-40°C to 85°C
8543BGILFT	ICS8543BGILF	"Lead-Free" 20 Lead TSSOP	Tape & Reel	-40°C to 85°C

NOTE: "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

Revision History Sheet

Rev	Table	Page	Description of Change	Date
А		3	Updated Figure 1, CLK_EN Timing Diagram.	10/17/01
А		3	Updated Figure 1, CLK_EN Timing Diagram.	11/2/01
A		1 6 - 10	Features section, Bullet 6 to read 3.3V LVDS levels instead of LVPECL. Updated Parameter Measurement Information figures.	5/6/02
В	45	1	Features - deleted bullet "Designed to meet or exceed the requirements of ANSI TIA/EIA-644".	9/19/02
	4E	5	LVDS Table - changed V _{OD} typical value from 350mV to 280mV.	
С	T2	2 4 9 10 11	 Pin Characteristics - changed C_{IN} 4pF max. to 4pF typical. Absolute Maximum Ratings - changed Output rating. Added Differential Clock Input Interface section. Added LVPECL Clock Input Interface section. Added LVDS Driver Termination section. Updated format throughout data sheet. 	1/5/04
D	T4B T9	1 3 4 10 11 12 13 15	Features section - added lead-free bullet. Updated Figure 1, CLK_EN Timing Diagram. LVCMOS DC Characteristics Table - corrected typo in V_{IH} max. from V_{DD} - 0.3V to V_{DD} + 0.3V. Updated <i>Differential Clock Input Interface</i> section. Updated <i>LVPECL Clock Input Interface</i> section. Added <i>Recommendation for Unused Input and Output Pins</i> section. Added <i>Power Considerations</i> section. Ordering Information Table - added lead-free Part/Order Number, Marking and note. Updated format throughout the datasheet.	2/27/08
E	Т5	1 6 7 9	Features Section - added Additive Phase Jitter bullet. AC Characteristics Table - added Additive Phase Jitter spec. Added Additive Phase Jitter Plot. Parameter Measurement Information - updated <i>Output Rise/Fall Time</i> diagram.	9/9/08
E	Т9	All 1, 10, 11 11 12 15	Updated format throughout the datasheet. Deleted HiPerClockS references throughout. Updated figure 4D. Updated LVDS Driver Termination section. Deleted quantity from Tape & Reel.	10/8/12
Е	Т9	15	Removed leaded orderable parts from the Ordering Information table	11/15/12

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